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**Český institut pro akreditaci, o.p.s.**  
(Czech Accreditation Institute)  
**Hájkova 2747/22, Žižkov, 130 00 Praha 3**

issues

according to section 16 of Act No. 22/1997 Coll., on technical requirements for products and on changes and amendments to some Acts, as amended

# **CERTIFICATE OF ACCREDITATION**

**No. 39/2026**

**Wabtec Inspection Technologies Czech s.r.o.**  
**with registered office Evropská 16/176, Vokovice, 160 00 Praha 6**  
**Company Registration No. 23193557**

**for the Calibration Laboratory No. 2371**  
**NDT Calibration Laboratory**

**Scope of accreditation:**

Calibration in the fields of length, testing of material properties and defects, and electrical quantities for Evident/Olympus flaw detectors and thickness gauges to the extent as specified in the appendix to this Certificate.

This Certificate of Accreditation is a proof of accreditation issued on the basis of assessment of fulfillment of the accreditation criteria in accordance with

**ČSN EN ISO/IEC 17025:2018**

In its activities performed within the scope and for the period of validity of this Certificate, the abovementioned Accredited Body is entitled to refer to this Certificate, provided that the accreditation is not suspended and the Accredited Body meets the specified accreditation requirements in accordance with the relevant regulations applicable to the activity of an accredited conformity assessment body.

This Certificate of Accreditation replaces, to the full extent, Certificate No.: 455/2025 of 11/09/2025, and/or any administrative acts building upon it.

**The Certificate of Accreditation is valid until: 11/09/2030**

**Prague: 26/01/2026**



Signed in the Czech original:  
Gor Petrosjan on 26/01/2026

**Jan Velíšek**  
Director of the Department  
of Testing and Calibration Laboratories  
Czech Accreditation Institute

This translation of the Czech original has been issued by: Eliška Frycová



Accredited entity according to ČSN EN ISO/IEC 17025:2018:

**Wabtec Inspection Technologies Czech s.r.o.**  
CAB number 2371, NDT Calibration Laboratory  
Evropská 16/176, Vokovice, 160 00 Praha 6

**CMC for the field of measured quantity: Length**

Ord. number 1	Calibrated quantity / Subject of calibration	Nominal range				Parameter(s) of the measurand	Lowest stated expanded measurement uncertainty <sup>2</sup>	Calibration principle	Calibration procedure identification <sup>3</sup>	Loca- tion
		min	unit	max	unit					
1*	Ultrasonic thickness gauges	0.150 mm	to	5.100 mm			0.005 mm 0.01 mm	Comparison with the value of a length standard	DOC-23-00018	
2*	Magnamike thickness gauges	0.250 mm	to	25.340 mm			0.005 mm	Comparison with the value of a length standard	DOC-23-00018	

<sup>1</sup> Asterisk at the ordinal number identifies the calibrations, which the Laboratory is qualified to carry out outside the permanent laboratory premises.

<sup>2</sup> The expanded measurement uncertainty is in accordance with ILAC-P14 and EA-4/02 M a part of CMC and it is the lowest value of the respective uncertainty. If not stated otherwise, its coverage probability is approx. 95 %. If not stated otherwise, the uncertainty values stated without a unit are relative to the measured value. The uncertainty value stated herein is based on the best conditions achievable by the laboratory; the uncertainty value of a specific calibration may be higher depending on the conditions of such a calibration. For identical extreme values of adjacent ranges, the lower uncertainty value always applies.

<sup>3</sup> If the document identifying the calibration procedure is dated only these specific procedures are used. If the document identifying the calibration procedure is not dated, the latest edition of the specified procedure is used (including any changes).

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**CMC for the field of measured quantity: Testing of properties and defects of materials**

Ord. number 1	Calibrated quantity / Subject of calibration	Nominal range				Parameter(s) of the measurand	Lowest stated expanded measurement uncertainty <sup>2</sup>	Calibration principle	Calibration procedure identification <sup>3</sup>	Loca- tion
		min	unit	max	unit					
1*	Olympus/Evident ultrasonic thickness gauges by automatic method Pulse repetition frequency  Transmit pulse voltage Pulse tail Pulse rise time Pulse duration Current operating range  Precision and resolution	3 Hz	to	3 kHz			1 %  2 % 2 % 0.8 % 0.8 % 1.5 %  0.15 %	Measurement with an oscilloscope (ČSN EN 15317)      Reading from the power supply (ČSN EN 15317) Comparison with a length standard value (ČSN EN 15317)	DOC-23-00018	
2*	Olympus/Evident ultrasonic flaw detectors by automatic method Stability after heating  - signal amplitude - signal position Display instability - signal amplitude - signal position Stability at voltage fluctuation - signal amplitude - signal position Transmit pulse voltage Pulse tail Pulse rise time Pulse duration Amplifier frequency response	5 % SH 5 % SW	to	100 % SH 100 % SW			0.14 % SH 0.12 % SW  0.14 % SH 0.12 % SW  0.14 % SH 0.12 % SW  3 % 3 % 2 % 2 % 2 %	Instrument display reading (ČSN EN 12668-1)	DOC-23-00019	

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Ord. number 1	Calibrated quantity / Subject of calibration	Nominal range				Parameter(s) of the measurand	Lowest stated expanded measurement uncertainty <sup>2</sup>	Calibration principle	Calibration procedure identification <sup>3</sup>	Loca- tion
		min	unit	max	unit					
	Equivalent input noise level	1 nV/√Hz	to	80 nV/√Hz		7 %	Calculation from measured values (ČSN EN 12668-1) Comparison with a reference attenuator (ČSN EN 12668-1) Simulation by el. signal (ČSN EN 12668-1)			
	Calibrated attenuator accuracy	0 dB	to	110 dB		0.7 dB				
	Display unit vertical linearity	5 % SH	to	100 % SH		1 % SH				
	Time base linearity	5 % SW	to	100 % SW		0.0004 % SW				
	Time resolution	50 ns	to	150 ns		2 ns				
	Transmit pulse voltage	2 V	to	500 V		3 %				
	Pulse rise time	2 ns	to	1100 ns		2 %	Measurement with an oscilloscope (ČSN EN ISO 22232-1)			
	Pulse duration	2 ns	to	1100 ns		2 %				
	Amplifier frequency response	0.1 MHz	to	26.5 MHz		2 %				
	Equivalent input noise level	1 nV/√Hz	to	80 nV/√Hz		7 %	Instrument display reading (ČSN EN ISO 22232-1) Calculation from measured values (ČSN EN ISO 22232-1) Comparison with a reference standard (ČSN EN ISO 22232-1) Simulation by el. signal (ČSN EN ISO 22232-1)			
	Calibrated attenuator accuracy	0 dB	to	110 dB		0.7 dB				
	Display unit vertical linearity	5 % SH	to	100 % SH		1 % SH				
	Time base linearity	5 % SW	to	100 % SW		0.0004 % SW				
3*	Olympus/Evident Nortec 500 series eddy current flaw detectors							DOC-23-00021		
	Instrument current demand	550 mA	to	850 mA		0.006 mA	Power supply reading			
	Instrument switching-off	7.0 V	to	8.0 V		0.06 V				
	Instrument charging current	1.0 A	to	1.7 A		0.5 mA	Measurement by a multimeter			
	Output signal amplitude	0.4 V	to	4.2 V		0.05 mV				
	Instrument driving pulse	8.20 V <sub>p-p</sub>	to	10.27 V <sub>p-p</sub>		0.06 V <sub>p-p</sub>				
	Instrument output frequency	0 Hz	to	100 Hz		0.1 Hz				

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		min	unit	max	unit					
	Filter test	0 MHz	to	12 MHz			$12 \cdot 10^{-6}$ MHz	Instrument display reading Measurement by an oscilloscope		
	Scanner output frequency	2 Hz	to	8 Hz			0.057 Hz			
	- for 1200 RPM	0 Hz	to	20 Hz			0.02 Hz	Comparison with a reference standard Measurement by an oscilloscope		
	- for 3000 RPM	0 Hz	to	50 Hz			0.05 Hz			
	Instrument conductivity	30 %IACS	to	60 % IACS			0.17 % IACS			
	Additional outputs Frequency No. 1 & No. 2			5 V			0.06 V			
4*	Olympus/Evident Nortec 600 series eddy current flaw detectors							Measurement with an oscilloscope (ČSN EN ISO 15548-1)	DOC-23-00021	
	Excitation frequency	$10 \cdot 10^{-6}$ MHz	to	10 MHz			2 %			
	Harmonic distortion	$10 \cdot 10^{-6}$ MHz	to	10 MHz			0.3 %	Instrument display reading (ČSN EN ISO 15548-1) Comparison with a reference attenuator (ČSN EN ISO 15548-1) Calculation from measured values (ČSN EN ISO 15548-1)		
	Maximum output voltage	1.8 V <sub>p-p</sub>	to	2.2 V <sub>p-p</sub>			0.3 %			
	Maximum permissible output voltage	0.1 V <sub>p-p</sub>	to	14.4 V <sub>p-p</sub>			0.5 %			
	Signal processing frequency response	0.1 kHz	to	2 kHz			0.1 %			
	Phase linearity	0 °	to	360 °			0.002°			
	Gain setting accuracy	0 dB	to	100 dB			0.07 dB			
	Instrument maximum noise	1.8 μV	to	15.0 μV			0.5 %			
5*	Olympus/Evident BondMaster 600 series eddy current flaw detectors							Measurement by an oscilloscope	DOC-23-00021	
	Excitation frequency	1 kHz	to	500 kHz			2 %			
	Harmonic distortion	$10 \cdot 10^{-6}$ MHz	to	10 MHz			0.3 %			

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		min	unit	max	unit					
	Maximum output voltage of TX generator (MIA, RESONANCE) and HV generator (MIA)	0.9 V <sub>P-P</sub>		140 V <sub>P-P</sub>			0.3 %			
	Output voltage linearity	0.01 %		0.75 %			0.5 %			
	Signal processing frequency response	70 Hz		80 Hz			0.1 %			
	Phase linearity	0 °		360 °			0.002°			
	Gain setting accuracy	0 dB		100 dB			0.07 dB			
	Instrument maximum noise	1.8 µV		15 µV			0.5 %			
6*	Olympus/Evident Omniscan series ultrasonic flaw detectors								DOC-23-00022	
	Stability after heating (mm)									
	- signal amplitude	5 % SH		100 % SH			0.14 % SH			
	- signal position	5 % SW		100 % SW			0.12 % SW			
	Display unit instability									
	- signal amplitude (mm)	5 % SH		100 % SH			0.14 % SH			
	- signal position (mm)	5 % SW		100 % SW			0.12 % SW			
	Stability at voltage variations									
	- signal amplitude (mm)	5 % SH		100 % SH			0.14 % SH			
	- signal position (mm)	5 % SW		100 % SW			0.12 % SW			
	Transmit pulse voltage	2 V		500 V			3 %			
	Pulse tail	2 V		500 V			3 %			
	Pulse rise time	2 ns		1100 ns			2 %			
	Pulse duration	2 ns		1100 ns			2 %			
	Amplifier frequency response	0.1 MHz		26.5 MHz			2 %			
	Equivalent input noise level	1 nV/√Hz		80 nV/√Hz			7 %			

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		min	unit	max	unit					
	Calibrated attenuator accuracy	0 dB		to	110 dB		0.7 dB	Comparison with a reference attenuator (ČSN EN 12668-1)		
	Display unit vertical linearity (mm)	5 % SH		to	100 % SH		1.0 % SH	Instrument display reading (ČSN EN 12668-1)		
	Time base linearity	0 µs		to	5,125 µs		0.004 µs	Simulation by el. Signal (ČSN EN 12668-1)		
	Transmit pulse voltage (PA)	2 V		to	500 V		3 %	Measurement by an oscilloscope		
	Pulse rise time (PA)	2 ns		to	1100 ns		2 %			
	Pulse duration (PA)	2 ns		to	1100 ns		2 %			
	Emission delay (PA)	0 ns		to	5 ns		0.08 ns			
	Bandwidth (PA)	0.2 MHz		to	26.5 MHz		2 %	Instrument display reading		
	Display linearity (PA)	5 % SH		to	100 % SH		0.23 % SH			
	Instrument absolute gain (PA)	5 % SH		to	100 % SH		0.23 % SH	Measurement with an oscilloscope		
	Display linearity delay (PA)	0.01 µs		to	10.01 µs		0.001 µs	Simulation by el. signal		
	Transmit pulse voltage (UT)	2 V		to	500 V		3 %	Measurement with an oscilloscope		
	Pulse rise time (UT)	2 ns		to	1100 ns		2 %			
	Pulse duration (UT)	2 ns		to	1100 ns		2 %			
	Instrument absolute gain (UT)	5 % SH		to	100 % SH		0.23 % SH			
	Bandwidth (UT)	0.2 MHz		to	26.5 MHz		2 %	Instrument display reading		
	Display linearity delay	0.01 µs		to	10.01 µs		0.001 µs	Simulation by el. signal		
	Display linearity	5 % SH		to	100 % SH		0.23 % SH	Instrument display reading		
	Transmit pulse voltage (UT)	2 V		to	500 V		3 %	Measurement with an oscilloscope		
	Pulse rise time (UT)	2 ns		to	1100 ns		2 %	(ČSN EN ISO 22232-1)		
	Pulse duration (UT)	2 ns		to	1100 ns		2 %			
	Amplifier frequency response	0.2 MHz		to	26.5 MHz		2 %	Signal generation (ČSN EN ISO 22232-1)		

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		min	unit	max	unit					
	Equivalent input noise level	1	nV/√Hz	80	nV/√Hz		7 %	Calculation from measured values (ČSN EN ISO 22232-1)		
	Calibrated attenuator accuracy	0	dB	110	dB		0.7 dB	Comparison with a reference attenuator (ČSN EN ISO 22232-1)		
	Display unit vertical linearity (mm)	5	% SH	100	% SH		1.0 % SH	Instrument display reading (ČSN EN ISO 22232-1)		
	Channel gain deviation	5	% SH	100	% SH		0.2 % SH	Instrument display reading		
	Transmit pulse voltage	2	V	500	V		3 %	Measurement with an oscilloscope (ČSN EN ISO 18563-1)		
	Pulse rise time	2	ns	1100	ns		2 %			
	Pulse duration	2	ns	1100	ns		2 %			
	Delay linearity	0	ns	100	ns		0.07 ns	Simulation by el. signal (ČSN EN ISO 18563-1)		
	Transmit channel position deviation	0	ns	5	ns		0.07 ns	Simulation by el. signal		
	Amplifier frequency response	0.2	MHz	29	MHz		2 %	Signal generation (ČSN EN ISO 18563-1)		
	Channel gain deviation	5	% SH	100	% SH		0.2 % SH	Instrument display reading (ČSN EN ISO 18563-1)		
	Equivalent input noise level	1	nV/√Hz	80	nV/√Hz		7 %	Calculation from measured values (ČSN EN ISO 18563-1)		
	Calibrated attenuator accuracy	0	dB	110	dB		0.7 dB	Comparison with a reference attenuator (ČSN EN ISO 18563-1)		
	Vertical display linearity (mm)	5	% SH	800	% SH		1 % SH	Instrument display reading (ČSN EN ISO 18563-1)		
	Linearity of individual transmit pulses	0	ns	55	ns		0.07 ns	Simulation by el. signal (ČSN EN ISO 18563-1)		
	Instrument absolute gain (ECA)	0	V	1.5	V		0.01 V	Measurement with an oscilloscope		
	Gain linearity (ECA)	0.1	%	3.0	%		0.7 %	Comparison with a reference attenuator		



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		min	unit	max	unit					
	Generator excitation frequency (ECA)	0.1 MHz		to	6.1 MHz		2.0 %	Measurement with an oscilloscope		
	Output voltage verification (ECA)									
	- voltage	1 V		to	10 V		0.7 %			
	- frequency	1 Hz		to	20 Hz		2.0 %			
	General test (ECA)									
	- voltage on a connector	0 V		to	12 V		0.08 V			
	- voltage on a BNC connector	0 V		to	12 V		0.08 V			

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#### Explanatory notes:

IACS..... International Annealed Copper Standard

RPM..... Revolutions per minute

SH..... Screen Height

SW..... Screen Width

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**CMC for the field of measured quantity: Electrical quantities**

Ord. number 1	Calibrated quantity / Subject of calibration	Nominal range				Parameter(s) of the measurand	Lowest stated expanded measurement uncertainty <sup>2</sup>	Calibration principle	Calibration procedure identification <sup>3</sup>	Location
		min	unit	max	unit					
1	DC voltage / DC voltage sources	0 mV	to	10 mV			8 µV	Direct measurement by a multimeter	DOC-25-00057	
		10 mV	to	100 mV			17 µV			
		100 mV	to	1 V			88 µV			
		1 V	to	10 V			0.8 mV			
		10 V	to	100 V			10 mV			
		100	to	1000 V			65 mV			
2	DC resistance	0 Ω	to	10 Ω			10 mΩ	Direct measurement by a multimeter	DOC-25-00057	
		10 Ω	to	100 Ω			29 mΩ			
		100 Ω	to	1 kΩ			0.2 Ω			
		1 kΩ	to	10 kΩ			2 Ω			
		10 kΩ	to	100 kΩ			20 Ω			
		100 kΩ	to	1 MΩ			0.2 kΩ			
		1 MΩ	to	10 MΩ			8 kΩ			
		10 MΩ	to	100 MΩ			0.9 MΩ			
3	HF voltage, peak-to- peak value / Sources of peak-to-peak voltage	2 mV	to	40 V		0,1 MHz to 100 MHz	3 % + 0.1 mV	Measurement with an oscilloscope with 50 Ω external load	DOC-25-00057	
4	VF attenuation / VF attenuator	0 dB	to	50 dB		0,25 MHz to do 100 MHz	0.17 dB	Measurement by a vector analyzer	DOC-25-00057	
		50 dB	to	60 dB			0.21 dB			
		60 dB	to	70 dB			0.28 dB			
		70 dB	to	80 dB			0.37 dB			
		80 dB	to	90 dB			0.57 dB			

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*"This document is an appendix to the certificate of accreditation. In case of any discrepancies between the English and Czech versions, the Czech version shall prevail, both for the certificate appendix and the certificate itself. "*